

What is claimed is:

1. A method for testing the crimped state of a terminal on the basis of a waveform of the characteristic values obtained in the process of crimping the terminal on a core of an electric wire, comprising the steps of:

acquiring a reference waveform from the characteristic waveform when the terminal has been crimped normally, and dividing the reference waveform into first plural reference waveform segments;

dividing a characteristic waveform obtained when a terminal to be tested is crimped on the electric wire into a plural segments corresponding to those of the reference waveform; and

deciding whether or not the crimped state of the terminal is good on the basis of the first reference waveform segments of the reference waveform and the waveform segments of the characteristic waveform.

2. A method of testing the crimped state of a terminal according to claim 1, wherein singular points of the reference waveform are previously acquired on the basis of increments of the reference waveform; and said first reference waveform segments contain said singular points.

3. A method of testing the crimped state of a terminal according to claim 1, wherein singular points of the reference

waveform are previously acquired on the basis of increments of the reference waveform; and said first reference waveform segments are located between the singular points.

5 4. A method for testing the crimped state of a terminal on the basis of a waveform of the characteristic values obtained in the process of crimping the terminal on a core of an electric wire, comprising the steps of:

acquiring a reference waveform from the characteristic waveform when the terminal has been crimped normally;

acquiring singular points of the reference waveform on the basis of the increments thereof;

acquiring second reference waveform segments which are segments containing the singular points;

10 15 acquiring second waveform segments containing the points corresponding to said singular points in the characteristic waveform obtained when the terminal to be tested has been crimped on the electric wire; and

20 deciding whether or not the crimped state of the terminal is good on the basis of said second reference waveform segments and said second waveform segments.

5 25 5. A method of testing the crimped state of a terminal according to claim 2, wherein said singular points are points where the increment of said reference waveform is maximum or zero.

6. A method for testing the crimped state of a terminal on the basis of a waveform of the characteristic values obtained in the process of crimping the terminal on a core of an electric wire, comprising the steps of:

5 acquiring a reference waveform from the characteristic waveform when the terminal has been crimped normally, and acquiring reference characteristic values at regular intervals of the reference waveform;

acquiring the characteristic values of the  
10 characteristic waveform obtained when the terminal to be tested has been crimped on the electric wire, at said regular intervals; and

deciding whether or not the crimped state of the terminal is good on said reference characteristic values and the  
15 characteristic values.

7. A method of testing the crimped state of a terminal according to claim 2, wherein said electric wire has a coating for coating said core,

20 said terminal has caulking legs for caulking said core, a first pooriness waveform is acquired from the waveform when said calking legs caulk said coating as well as said core, and

a first singular point of said singular points is acquired  
25 from said reference waveform and said first pooriness waveform.

8. A method of testing the crimped state of a terminal according to claim 7, wherein said first singular point is defined by a point where the characteristic value of said first poorness waveform exceeds that of said reference waveform as the time of a crimping operation elapses.

9. A method of testing the crimped state of a terminal according to claim 2, wherein

said core is composed of a plurality of conductors tied up in a bundle;

said terminal has caulking legs for caulking said core; a second poorness waveform is acquired from the characteristic waveform when said caulking legs caulk conductors whose number is smaller than that when the terminal has been normally crimped; and

a second singular point is acquired from said reference waveform and said second poorness waveform.

10. A method of testing the crimped state of a terminal according to claim 9, wherein said second singular point is defined by a point where the characteristic value of said first poorness waveform falls below that of said reference waveform as the time of a crimping operation elapses.